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Information Disclosure Statement By Applicant				Applicant: Mieher, et al.			
(Use Several Sheets if Necessary)				Filing Date February 23, 2005	Group 2877		

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Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
GS	D1	WO/9956174	04.11.99	WIPO	G03B	27/42	X	
	D2	11-86332	3-30-99-	JAPAN 07/1989	G11B	7/135		X
	D3	JP 60-126881	86.07.06	JAPAN	H01S	3/18		X
	D4	JP 63-248804	10.17.88	JAPAN	C08F	10/00		X
	D5	WO/85/04266	26.09.85	WIPO	G03B	41/00	X	
	D6	WO/95/02200	19.01.95	WIPO	G02B	5/18	X	
	D7	WO03042629	22.05.03	WIPO	G01B	11/00	X	
	D8	WO/03054475	03.07.03	WIPO	G01B	11/06	X	
	D9	WO/0218871	07.03.02	WIPO	G01B	11/27	X	
	D10	WO 02/065545	22.08.02	WIPO	H01L	21/66	X	
	D11	WO/0215238	21.02.02	WIPO	H01L	21/00	X	
	D12	WO 01/97279	20.12.01	WIPO	H01L	21/66	X	
	D13	WO 02/35300	02.05.02	WIPO	G05B	19/00	X	
	D14	WO 02/25723	28.03.02	WIPO	H01L	21/66	X	
	D15	WO 99/45340	10.09.99	WIPO	G01B	11/02	X	
	D16	WO 0250509	27.06.02	WIPO	G01N		X	
	D17	WO 03/001297	03.01.03	WIPO	G03F	G03F	X	
	D18	WO 02/084213	24.10.02	WIPO	G01B	11/00	X	
✓	D19	WO02/25708	28.03.02	WIPO	H01L	21/00	X	
	D20	WO01/84382	08.11.01	WIPO	G06F	17/50	X	
Examiner /Gordon Stock Jr/				Date Considered 09/26/2006				

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.